Comments and Corrections

Corrections to "Probabilistic Simulation for Reliability Analysis of CMOS VLSI Circuits"1
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Abstract—Due to difficulties with mail service, the authors' corrections to the galley proofs were not incorporated into the above paper.1

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The editorial staff apologizes to the authors and readers for this problem.

The corrections are as follows.
1) Equation (3.4) should read:

\[ E[\bar{r}] = V_{ad} \times E[G_p(t^+)G_p(t^-) = 0] \times P(G_p(t^-) = 0) \]

(3.4)

2) The left-hand-side of (4.14) should be \( P_{e_1f-h_1}(t) \), not \( P_{e_1f-h_1}(t^+) \).

3) The table shown under the title and caption of "Table I" ("Table II") is actually Table II (Table I).

4) Equation (A.1) should read:

\[ P_{e_1}(t^+) = P_{e_1}(t^+) + P_{e_1}(t^+) - P_{e_1}(t^+) P_{e_1}(t^+) \]

(A.1)